

Notice of References Cited

Application/Control No.

10/516,641

Applicant(s)/Patent Under
Reexamination
HAMALAINEN ET AL.

Examiner

David Q. Nguyen

Art Unit

2617

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0173329	11-2002	Hwang, Woonhee	455/522
*	B	US-6,850,770	02-2005	Hwang, Woonhee	455/522
*	C	US-6,738,646	05-2004	Miyoshi et al.	455/561
*	D	US-2003/0003942	01-2003	Okumura, Yukihiko	455/522
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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